Sidet Facilities

- A snap shot of space and equipment at Sidet and their current use
- Projected future uses and upgrades

Major Sidet Work Areas

Location	Size(Sqf)	Designed Class	No. Volume changes/hour
Lab C north	1750	10,000	15
Lab C south	1600	10,000	15
Lab D	2350	10,000	30
Bonding room	720		
Repair stations	300		
C-D cross connect	t 2000		
A-B bridge east	500		
A-B bridge west	780		

Temperature Uniformity Study (Winter '06)

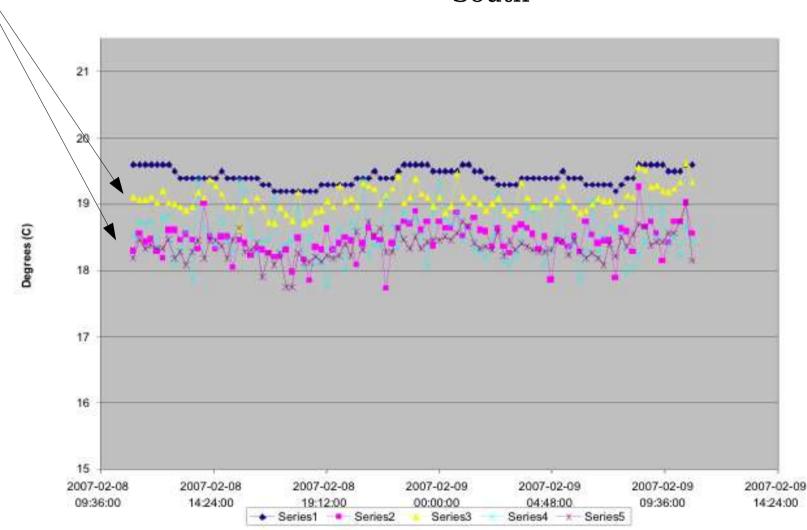
Preliminary!

	V	ariations (Cele	cius)
Area	Daily	Horizontal	Vertical
	J		
Lab C North	1-2	1	1-2
Lab C South	1-2	1	1-2
Lab D	1-2	1	2-3

Preliminary!

Vertical span of 8'

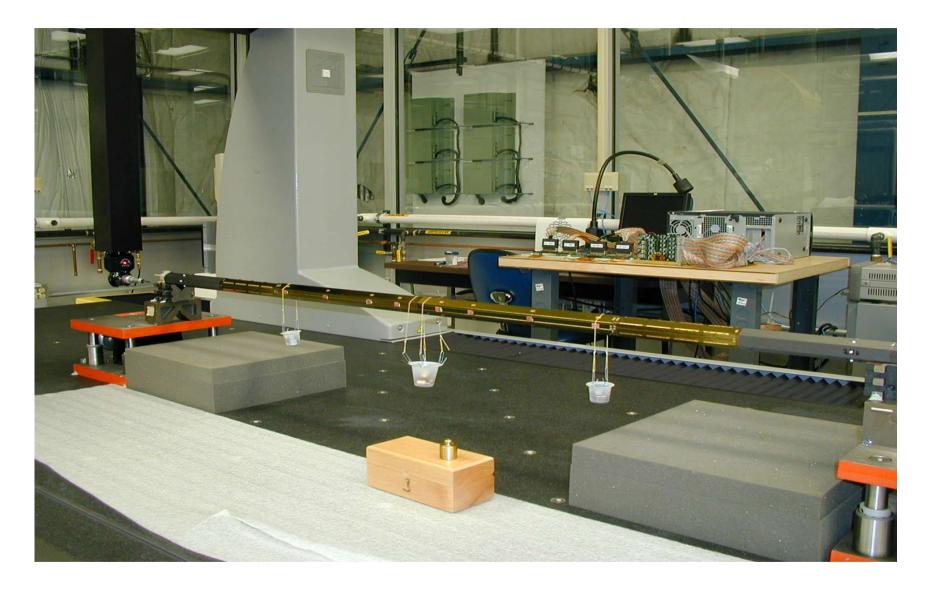
Temperature Uniformity Near Brown&Sharp CMM in Lab C South



CMM INFORMATION

	Machine	Location	Measuring Range	Machine	Overall Dimensions	Table	CTE of scales
	i i	3 19	XYZ (mm)	Weight (lb)	WxLxH(mm)	Height(in)	PPM/degree C
		3 19		1012000000			
Cordax	1808-MH	Lab D	1500x625x500	4900	2134x1293x2660		C
are one resign	1808-MEA-1	Lab D	750x625x500	3200	1372x1293x2660		8
	1808-MEA-2	Lab D	750x625x500	3200	1372x1293x2660		\$ \$
LK	LK G80C	Lab C	2000x1000x800	17257	1821x2896x3091	28	X(10),Y(10),Z(10)
	LK HC90	Lab 3	4000x1600x1600	14868	3	NA	X(10),Y(10),Z(10)
Zeiss	UMM500-1 (500-3)	Lab D SE	500x200x300	3219	*		e
	UMM500-2	Lab D NW	500x200x300	3219			
	UMM500-3	Lab A	500x200x300	3219	3		
	UMM500-4	Lab D SW	500x200x300	3219			
	UMC850-5	Lab C	850x1200x600	8377		36	<u> </u>
	UPMC850-6	Lab D	850x700x600	7385	3	36	
	UMM500-7	Lab C	500x200x300	3219	3		(s
	UMM500-8	Lab D NE	500x200x300	3219			# #
BnS	Global Image 12-30-10	Lab C	1200x3000x1000	16285	1811x4445x3330	24	X(10),Y(10),Z(10)
0.000	Global Image 9-15-8	Lab C	900x1500x800	5218	1509x2794x3066	28	X(10),Y(10),Z(10)
	XCEL UHA 12-30-10	Lab C	1200x3000x1000	27500	2040x4225x3738	39	X(8.6),Y(7.8),Z(8.6
	XCEL 9-15-9	Lab C	900x1500x900	10400	1735x2625x3170	30	X(8.6),Y(7.8),Z(8.6
OGP	Avant 600	Lab D	610x450x150	3340	1020x1320x1730		X(9.4),Y(9.4),Z(9.4)

Brown & Sharp Global Image CMM with Touch Probe 200



Touch Probe 200 Force = 2-10 grams Feather Probe Force < 10 mgrams (not shown)

ACCURACY SPECIFICATIONS

	Machine	Lin. Acc. B89	Lin. Acc. VDI	Vol. Acc B89	Vol. Acc. VDI	Planar Acc. VI
	Waciline	mm / mm	L = length in mm	mm / mm	L = length in mm	L = length in m
	1	311017.0101	result is in um	3111117 111111	result is in um	result is in um
	8	8	result is in uni	-	result is in uni	result is in un
CORDAX	1808-MH	.010 / 1500		.017 / 400		
	1808-MEA-1	.007 / 750		.016 / 400		
	1808-MEA-2	.007 / 750		.016 / 400		8
LK	LK G80C	*	*	.013 / 400		
	LK HC90	8		*		
ZEISS	UMM500-1	0	0.5 + L/700	.008 / 450		2
	UMM500-2		0.5 + L/700	.008 / 450		
	UMM500-3		0.5 + L/700	.008 / 450		
	UMM500-4		0.5 + L/700	.008 / 450		
	UMC850-5	3	1.9 + L/300		3.0 + L/200	
	▶ UPMC850-6	3	0.5 + L/900		0.8 + L/600	
	UMM500-7		0.5 + L/700	.008 / 450		
	UMM500-8	**************************************	0.5 + L/700	.008 / 450		
BNS	Global Image 12-30-10	.006 / 3000		.008 / 900	1.9 + L/333	
	Global Image 9-15-8	.006 / 1500		.007/ 750	2.5 + L/333	
	XCEL UHA 12-30-10	.010 / 3000	3.6 + L/322	.011 / 900	3.9 + L/303	
	XCEL 9-15-9	.007 /1500	4.0 + L/244	.010 / 750	4.4 + L/233	
OGP	Avant 600	2.		7		4.0 + L/150

Other Major Equipment

Generic Equipment

- Wire bonders
- Dicing Saw
- Vacuum Ovens and Clean Benches
- Encapsulation machines (manual and automatic)
- Alcatel Leak checker
- Inspections Stations
- Probe stations
- Electronics Modules (e.g. Keithley 237's)
- Chillers
- Vacuum pumps
- Plasma Cleaner (needs to be recommissioned)
- Flip-Chip Bonder (on arrival)

Project Specific Equipment

- SVX readout infrastructure
- Burnin Boxes

Vacuum Oven and Clean Bench Workstation in Lab D





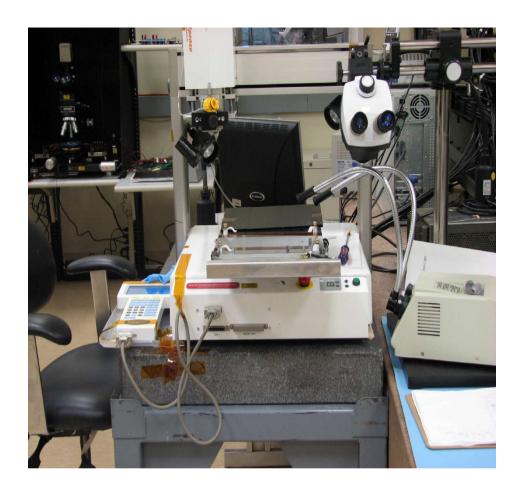
Currently used by CMS-FPIX for lamination





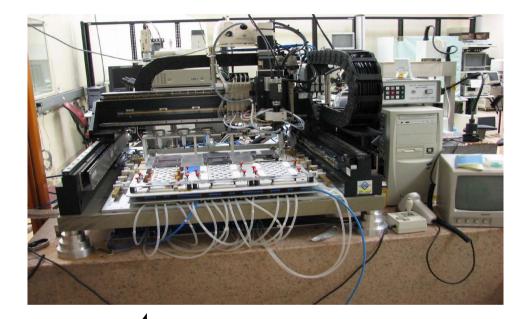
We will be receiving a flip-chip bonder in the summer.

We are exploring upgrading to a deep-head bonder.



Encapsulation Robot in Lab D

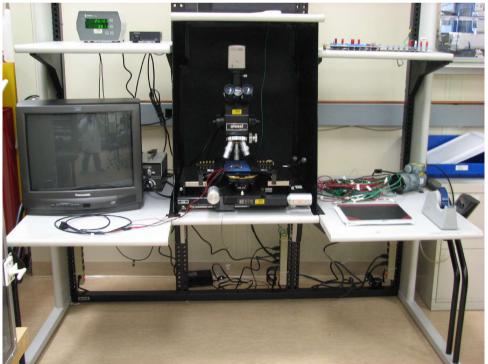
Omis-II X-Y inspection stations (~4 total)



Aerotech Gantry (Specific to CMS-TOB)

Probe stations (~4 total)





Inspection Optics and CCD camera

<u>Device</u>	<u>Magnification</u>	Pixel resolution	Field of View
	J		
Ram	2x	0.6 microns	0.46 mm x 0.46 mm
OGP	5x	0.5 microns	0.45 mm x 0.45 mm
Nikon	20x	-	0.15 mm x 0.15 mm
AEI	450x	-	0.7 mm x 0.7 mm

Typical working distance of 30 mm

Chillers (all currently in use)

4 small Neslab bath chillers. -5C. Low wattage

2 medium glycol chiller -5C. 10 watts

1 medium glycol-PF50 chiller with heat-exchanger X X

1 large glycol chiller -20C. 20 Watts

1 FTS PF50 chiller X large 1 FTS PF50 chiller X large (Univ of Rochester)

Space and Equipment Usage

Projects (Other than ILC Silicon R&D)

CMS-FPIX

Lab C North, Lab D
C-D cross connect

Lab C South, Lab A

RD50

Lab C South (Small)

ILC SiliconPM R&D A-B bridge test area

LANL-Phenix Forward Planar Pixel

Lab D (small) and
A-B brige test area

BNL-Phenix Layer3-4 Wirebonding

and Encapsulation

Lab D (small) and

A-B bridge test area

Silicon Pixel Testbeam Support

Lab D (small) and
A-B bridge test area

Super CDMS Lab D (small)

COUPP Lab D (small)

Other Projects (in discussion) -----

Space Usage Forecast

DES/SNAP will occupy Lab C South for long term.

CMS-FPIX Panel Assembly concludes in Summer 2007. Significantly more space and equipment in Lab D and C-D cross connect will be available.

CMS-FPIX Full Detector Assembly concludes in Fall-Winter 2007. Significantly more space and equipment in Lab C North will be available.

We do not know yet the impact of other projects that are in discussion: SLHC upgrade, and other DOE silicon projects based elsewhere.

I expect that priority will be given to ILC Silicon R&D in lab D.

Clean room space is also available at Lab 3, in the village (5 minutes drive from Sidet).

Rated at class 10,000.

Size comparable to Lab C.

This space would have to be shared with SuperCDMS, COUPP.

Manufacturer Specifications

	Global Image 12-30-10	XCEL 9-15-9	OGP
B89 Linear Accuracy (mm/mm)	.006 / 3000	.007 /1500	g
VDI/VDE Linear Accuracy (um)	.000 0000	4.0 + L/244	
B89 Volumetric Accuracy (mm/mm)	.008 / 900	.010 / 750	52
VDI/VDE Volumetric Accuracy (um)	1.9 + L/333	4.4 + L/233	
B89 Repeatability (um)	0.002	0.002	
XY Planar Accuracy (um)	ğ	200000000	4.0 + L/150
Z Linear Accuracy (um)			4.0 + L/150
	The state of the s		NO. THE WORLD CO.

L = length in mm

VDI/VDE - European standard for CMM performance evaluations

B89 - U.S. standard for CMM performance evaluations

B89 Repeatability - range of center coordinates of a sphere determined by 10 successive sphere measurements

B89 Linear Accuracy - conformance of the CMM scales to the international standards - designated as range of all measured deviations

B89 Volumetric Accuracy - assessment of total geometry of CMM structure - designated as range of all measured deviations

Video Probe Repeatability and Working Distance

Ram	Nikon	OGP
38	47.5	35
2	2	1
1	1	3
23	9	5
7.0	2.7	1.6
	38 2 1 23	38 47.5 2 2 1 1 1 23 9

Repeatability - range of center coordinates of a sensor target determined by 25 successive measurements

Estimated Video Probe Reference Accuracy and Drift

	Ram	Nikon	OGP
Video to Touch Probe Reference Accuracy XY (um)	3	3	2
Video to Touch Probe Reference Accuracy Z (um)	10	5	3
Video Probe Drift XY (um)	10	10	2
Video Probe Drift Z (um)	10	10	2

Drift - changes in measured values due to environmental factors such as temperature variation

All estimates of video probe reference accuracy and drift are based on experience.

Official tests to evaluate video probe measurement uncertainty have not been conducted but are being planned